Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10581959	YOON, IL SHIK
Examiner	Art Unit

3654

SEARCHED						
Class	Subclass	Date	Examiner			
187	314, 393, 401, 414,	03/17/2008	SHK			
52	220.8, 717.01, 718.01, 506.01 - 506.09					
248	544, 237, 221.11, 301, 323, 343					
B66B	13/02, 11/02, 7/00					
454	68,292, 370					

Stefan Kruer

SEARCH NOTES			
Search Notes	Date	Examiner	
PLUS	03/17/2008	SHK	

INTERFERENCE SEARCH				
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